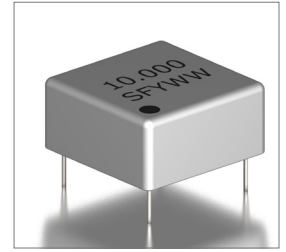
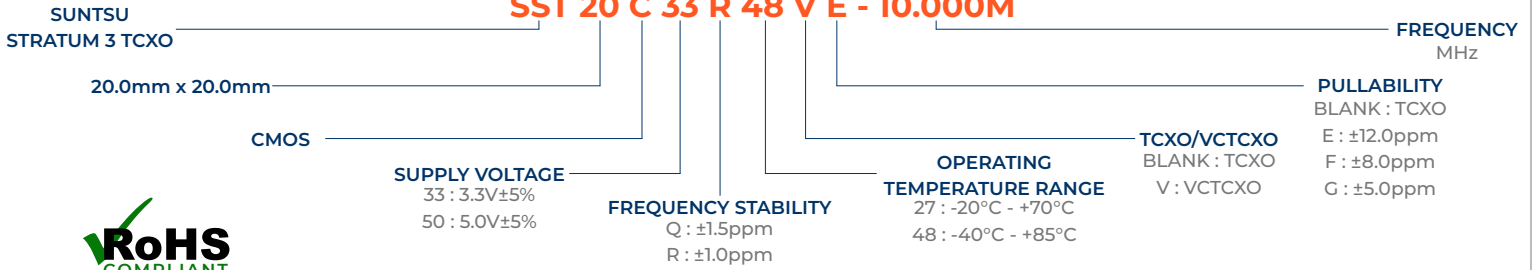


Features
<ul style="list-style-type: none"> Stratum 3 (Overall ± 4.6ppm) CMOS (VC)TCXO

Applications
<ul style="list-style-type: none"> Base Stations Stratum 3


Part Numbering Guide
SST 20 C 33 R 48 V E - 10.000M


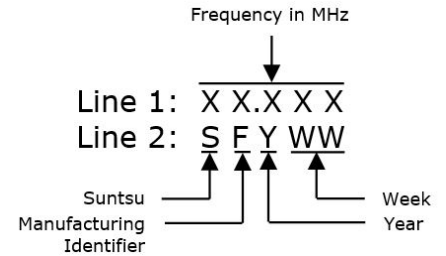
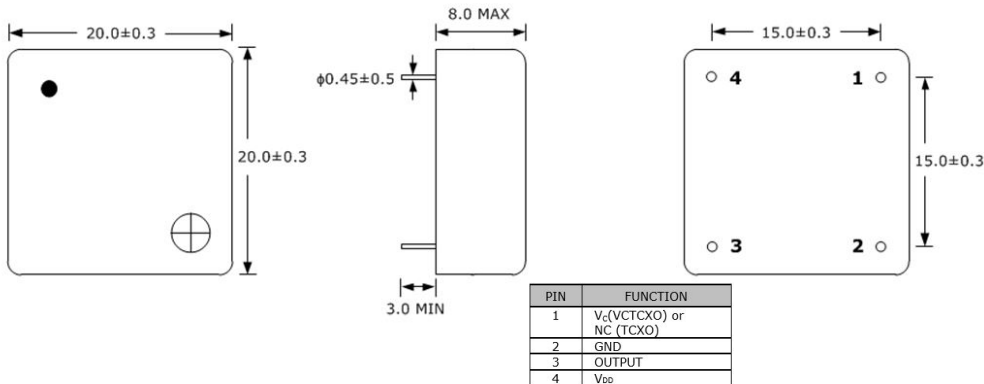
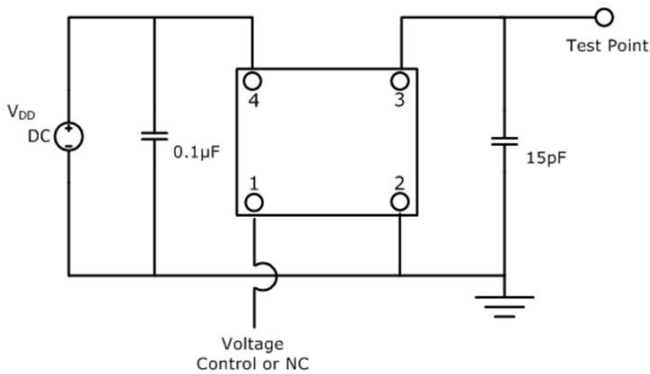
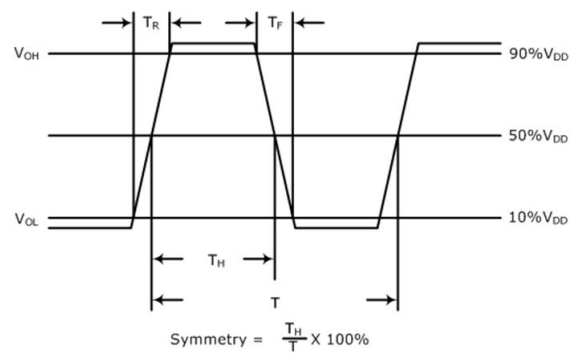
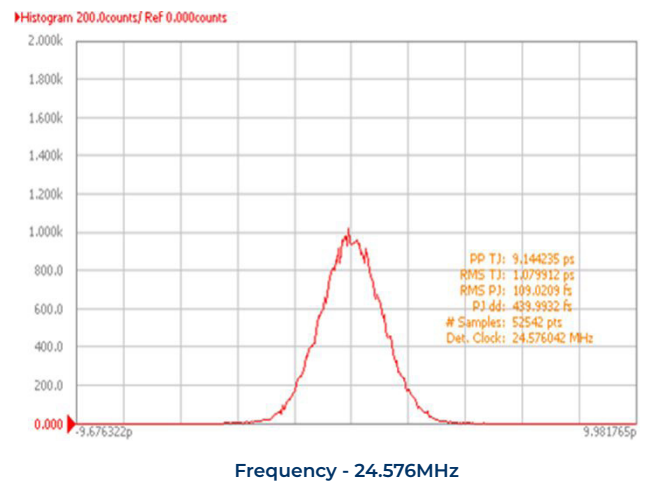
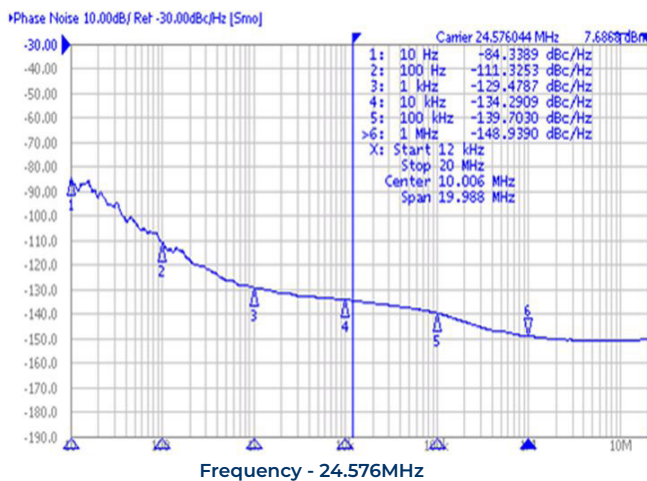
Cage Code: 4GUT4

To customize your parameters contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	2		150	
Frequency Tolerance at +25°C	ppm	-0.3		+0.3	
Freq. Stability vs. Op Temp.	ppm	-1.0		+1.0	See part numbering guide for options.
Freq. Stability vs. Supply Voltage	ppm	-0.1		0.1	V _{DD} \pm 5% Change
Freq. Stability vs. Load	ppm	-0.1		0.1	\pm 5% Change
Freq. Stability vs. Aging/Year	ppm	-1.0		1.0	1 year, \pm 2.6ppm for 10years
Operating Temperature	°C	-40		+85	See part numbering guide for options.
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 3.3V Option	V	3.135	3.3	3.465	
Supply Voltage (V _{DD}) - 5.0V Option	V	4.750	5.0	5.250	
Current (I _{DD})	mA			20	
Voltage (VC, VCTCXO) - 3.3V Option	V	0.3		3.0	
Voltage (VC, VCTCXO) - 5.0V Option	V	0.5		4.5	
Pullability (VCTCXO)	PPM	\pm 5.0		\pm 12.0	See part numbering guide for options.
Linearity (VCTCXO)	%			20	
Output Load (CMOS)	pF			15	
Output Logic Level High (V _{OH})	V	0.9*V _{DD}			
Output Logic Level Low (V _{OL})	V			0.1*V _{DD}	
Rise (T _R) And Fall (T _F) Time	ns			10	
Symmetry (Duty Cycle)	%	40	50	60	
Start-Up Time	ms			10	
Frequency Adjustment	ppm	3			
Phase Noise (Typical) 10Hz Offset	dBc/Hz		-70		
Phase Noise (Typical) 100Hz Offset	dBc/Hz		-115		
Phase Noise (Typical) 1KHz Offset	dBc/Hz		-132		
Phase Noise (Typical) 10KHz Offset	dBc/Hz		-144		
Phase Noise (Typical) 100KHz Offset	dBc/Hz		-150		

Outline Drawing & Part Marking

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.


Test Circuit (CMOS)

Waveform (CMOS)

Typical Phase Noise And Jitter Performance (Measured By Agilent E5052A)


Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K